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# **Preliminary User's Manual**

QB-703425

(IECUBE for V850E/Dx3)

# **Target Devices:**

μPD703420 μPD70(F)3421 μPD703422 μPD70F3423 μPD70F3424 μPD70F3425

#### NOTES FOR CMOS DEVICES —

### (1) VOLTAGE APPLICATION WAVEFORM AT INPUT PIN

Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between  $V_{IL}$  (MAX) and  $V_{IH}$  (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between  $V_{IL}$  (MAX) and  $V_{IH}$  (MIN).

### (2) HANDLING OF UNUSED INPUT PINS

Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.

#### **③ PRECAUTION AGAINST ESD**

A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.

### **4** STATUS BEFORE INITIALIZATION

Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.

### (5) INPUT OF SIGNAL DURING POWER OFF STATE

Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.

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### Introduction

Target Readers This manual is intended for users who design and develop application systems

using the V850E/Dx3.

**Purpose** The purpose of this manual is to describe the proper operation of the

QB-703425, and its basic specifications.

**Organization** This manual is broadly divided into the following parts.

Overview

Setup procedure

Cautions

#### How to read this manual

It is assumed that the reader of this manual has general knowledge in the fields of electrical engineering, logic circuits, and microcontrollers. This manual explains the basic setup procedure, so read this document before using the QB-703425.

To learn about the basic specifications and operation methods.

→ Read this manual in the order of the **CONTENTS**.

To learn about software settings such as operation methods and command functions.

→ Read the user's manual of the debugger that is used.

**Legend** Symbols and notation are used as follows:

Weight in data notation : Left is high-order column, right is low order column

Active low notation :  $\overline{xxx}$  (pin or signal name is over-scored) or

/xxx (slash before signal name)

Memory map address: : High order at high stage and low order at low stage

Note : Explanation of (Note) in the text

**Caution** : Item deserving extra attention

**Remark** : Supplementary explanation to the text

Numeric notation : Binary... xxxx or xxxB

Decimal... xxxx

Hexadecimal... xxxxH or 0x xxxx

Prefixes representing powers of 2 (address space, memory capacity)

K (kilo):  $2^{10} = 1024$ 

M (mega):  $2^{20} = 1024^2 = 1,048,576$ G (giga):  $2^{30} = 1024^3 = 1,073,741,824$ 

### Introduction

## **Terminology** The meanings of terms used in this manual are listed below.

Term	Meaning
Target device	Refers to the device targeted for emulation.
Target system	Refers to the system targeted for debugging. This includes the target program and the hardware created by the user. In the narrow sense, it means hardware only.

Related Documents When using this manual, refer to the following manuals.

The related documents indicated in this publication may include preliminary versions.

However, preliminary versions are not marked as such.

• Documents related to development tools (user's manuals)

Document Name		Document Number
QB-703425 In-Circuit Emulator		This manual
QB-703425 In-Circuit-Emulator Option Board Operating Precautions Target	Customer Notification	EEDT-OP-0027 - current version
CPDW9X/NT-CDR-V85X	GHS integrated development environment (PC, MS Windows based)	Ver.4.07 or - current version
V850 Series CPDW9X/NT-CDR-V85X Operating Precautions MULTI 2000 Integrated Development Environment	Customer Notification	DTOP0010V30 - current version
850eserv / Detailed information listing	Read Me File for 850ESERV	850eserv.txt - current version
IEQBUTL / IECUBE Utility	Read Me File for IECUBE Utility IEQBUTL	IEQBUTL_E2.03c.txt or - current version

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#### Introduction

### **General Cautions on handling this product**

- 1. NEC Electronics' warranty does not cover the following cases:
  - When the QB-703425 is disassembled, reconstructed, or modified by the user
  - When the QB-703425 receives a heavy shock such as being dropped or falling down
  - When the QB-703425 is used with excessive voltage or is stored outside the guaranteed temperature range or guaranteed humidity range
  - When power is applied while the AC adapter, USB interface cable, or target system is not connected securely
  - When the AC adapter cable, USB interface cable, or extension probe is excessively twisted or stretched
  - When an AC adapter other than the one supplied with the QB-703425 is used
  - When water is spilled on the QB-703425

#### 2. Cautions on safe use

- The QB-703425 heats up (to approx. 50 to 60°C) when it operates for a long time. Take care not to receive injuries such as burns from a rise in the temperature.
- Be very careful to avoid electric shocks. There is risk of electric shock if the product is used as described in item 1 above.

[MEMO]

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## Chapter 1 Overview

The QB-703425 (IECUBE) is an in-circuit emulator used to emulate the V850E/Dx3 devices. By using IECUBE, hardware and software can be debugged efficiently in system development.

In this manual, the basic setup procedure, hardware specifications, system specifications, and switch settings are described.

This document describes the QB-703425 as IECUBE.



Figure 1-1: IECUBE

## 1.1 Hardware Specifications

Table 1-1: QB-703425 Hardware Specifications

Item		Specification
Target device		V850E/Dx3
Target system interface voltage (unit: V)		$\begin{aligned} & DV_{DD5} = 3.0 \; V \sim 5.5 \; V, \\ & BV_{DD5} = 3.0 \; V \sim 5.5 \; V, \\ & AV_{DD} = 3.2 \; V \sim 5.5 \; V, \; SMV_{DD5} = 3.2 \; V \sim 5.5 \; V, \\ & V_{DD5} = 3.2 \; V \sim 5.5 \; V, \\ & V_{SS5} = BV_{SS5} = DV_{SS5} = SMV_{SS5} = AV_{SS} = 0 \; V \end{aligned}$
Maximum oper	ating frequency	48 MHz + SSCG modulation range
Operating temperature range		0 to 40°C (without condensation)
Storage temperature range		-15 to 60°C (without condensation)
Package dimensions		See below
Power	AC adapter for IECUBE	15 V, 1 A
consumption	Target system power supply	Lower than that of target device
Weight		475 g - 537 g
Host interface		USB interface (1.1 and 2.0)

112.7 mm Notes 1, 6
128.0 mm

84.6 mm Note 2

68.0 mm Notes 3, 5
78.5 mm
89.0 mm

Rear spacer

Figure 1-2: IECUBE Dimensions

**Notes: 1.** Not including projection of power supply switch.

- 2. Including projection of screw for fixing rear spacer
- 3. Shortest dimension for the rear spacer (+30 mm max.)
- 4. The front spacer dimension is variable between 20 mm (max.) and 5 mm (min.)
- **5.** The height dimension (68.0 mm / 78.5 mm / 89.0 mm) depends on the count of option boards
- **6.** The fan at the back increase the length to 128.0 mm.

## 1.2 System Specifications

Table 1-2: QB-703425 System Specifications

	Function	Specification
Emulation	Internal ROM	1 Mbyte (Maximum)
Mamary conscity	Internal RAM	60 Kbyte (Maximum)
Memory capacity	External memory	None
Program execution function	Real-time execution function	Go, Start From Here, Go & Go, Come Here, Restart, Return Out
Turiction	Non-real-time execution function	Step In, Next Over, Slow Motion
	Hardware break	Execution: 10 points Access: 6 points
Break function	Software break	2000 points (debugger related)
	Fail-safe break	Non-map, I/O illegal, write protect
	Other	Trace full break, Manual Break, Timer Over Flow Break
	Trace data type	Branch source PC, branch destination PC, all PCs, all execution data, access data, access address, R/W status, time stamp, DMA point (start/end)
Trace function	Trace mode	Speed Priority, Trace Priority
	Trace event	Delay trigger, section, qualify
	Memory capacity	256k frames
Real-time RAM mor	nitor function	256 bytes × 8 points
	Measurement clock	Measurement-dedicated clock or CPU clock
	Measurement target	Program execution start to end Start event to end event
	Maximum measurement time	About 195 hours (when measurement-dedicated clock is used)
Time measure- ment function	Minimum resolution	20 ns
	Number of timers used for measurement	8
	Measurement result	Execution time (execution start to end) Max., min., Average, pass count (between events)
	Other	Timer overflow break function (1 point)
Coverage function		Optional (under development)
Other functions		Mapping function, event function, register manipulation function, memory manipulation function

Caution: Some of the functions may not be supported, depending on the debugger used.

### 1.3 System Configuration

The system configuration when connecting the QB-703425 to a PC (PC98 series or PC/AT compatible) is shown below. USB interface that enables communication based on USB (Ver1.1 or Ver2.0).

Connection is possible without optional products.

Connectors vary depending on the target device to be emulated.

Order code for the package is QB-703425-MZZ-EE.

IECUBE In-circuit emulator USB cable ICE <-> PC AC adapter cable Flash programmer Extension probe QB-208-EP-01S Exchange adapter QB-\*-EA-\*T Space adapter шиши QB-\*-YS-\*T ICE connector QB-\*-YQ-\*T Mount adapter QB-\*-HQ-\*T Target connector QB-\*-NQ-\*T Target system

Figure 1-3: Typical System Configuration

One piece of a special space adapter is included on the QB-208-EA-01T. This is required for using this exchange adapter without extension probe.

Figure 1-4: Target Probe

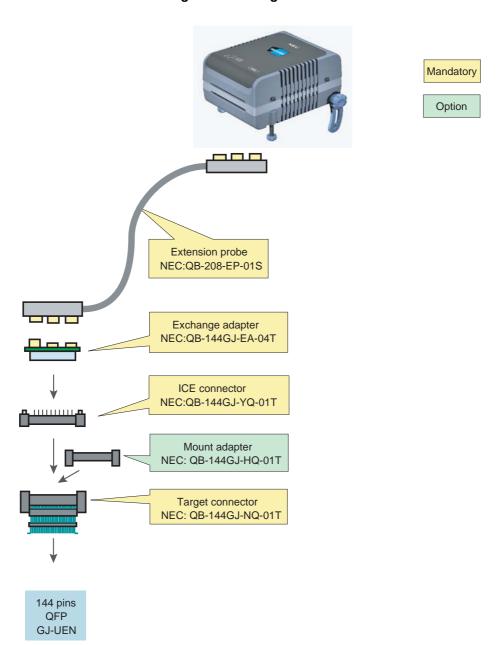


Table 1-3: List of Probes and Connectors for Each Target Device

No.	Name	Target Device to Be Emulated	
		V850E/DJ3 μPD70(F)342x-GJ-UEN: 144 QFP (20 mm × 20 mm / 0.5 mm)	
<6>	Extension probe (coaxial type)	QB-208-EP-01S (sold separately)	
<7>	Spacer adapter	QB-144GJ-YS-01T (sold separately) <sup>Note</sup>	
<8>	Exchange adapter	QB-144GJ-EA-04T (sold separately) <sup>Note</sup>	
<9>	YQ adapter	QB-144GJ-YQ-01T (sold separately)	
<10>	Mounting adapter	QB-144GJ-HQ-01T (sold separately)	
<11>	Target connector	QB-144GJ-NQ-01T (sold separately) <sup>Note</sup>	

**Note:** The accessories included with this product are as shown below.

When QB-703425-MZZ-EE is ordered:
 The exchange adapter and target connector are not included.

The QB-144GJ-YQ-01T includes different than standard YQGUIDE's, named YQGUIDE-S3. "YQGUIDE-S3" is attached between YQ and EA. This must be observed by customer.

### 1.4 Packing Contents

The packing box of the QB-703425-MZZ-EE contains the following. Make sure that these items are included.

- Items included with QB-703425-MZZ-EE
  - (1) QB-703425 In Circuit Emulator
  - (2) AC adapter
  - (3) USB interface cable
  - (4) PG-FPL flash programmer
  - (5) Readme First
  - (6) Registration Card
  - (7) CE "Note"
  - (8) QB-703425-MZZ-EE package contents list

### **Chapter 2 IECUBE Setup Procedure**

This chapter describes the procedure for setting up the QB-703425.

Perform setup using the following procedure.

See 2.1 "Names and Functions of Hardware" on page 24 for the positions of switches and clocks.

### (1) Clock settings

A 4.000 MHz crystal is mounted at shipment for main clock.

A 32.768 kHz crystal is mounted at shipment for sub clock.

The Ring clock is generated internally only.

There is no need to change the setting. When different type of crystal (e.g. same as on the target system) shall be used, follow instructions given in this manual.

See 2.2 "Removing Acrylic Board" on page 25 and 2.3 "Clock Settings" on page 26 when changing the crystal.

### (2) Target device setting

It is assumed that the IECUBE target device is the V850E/Dx3 at shipment.

There is no need to change the setting when emulating the V850E/Dx3.When different emulation option shall be used, follow instructions given in this manual.

See 2.2 "Removing Acrylic Board" on page 25 and 2.4 "Target IECUBE Settings" on page 28 when changing emulation options.

### (3) Software setup

See 2.5 "Software Setup" on page 28.

#### (4) Mounting and connecting connectors

See 2.6 "Mounting and Connecting Connectors" on page 30.

### (5) Connecting IECUBE to target system

See 2.7 "Connecting IECUBE to Target System" on page 33.

- When extension probe (QB-208-EP-01S) is used: See 2.7.1.
- When extension probe (QB-208-EP-01S) is not used: See 2.7.2.

### (6) Connecting USB interface cable and AC adapter

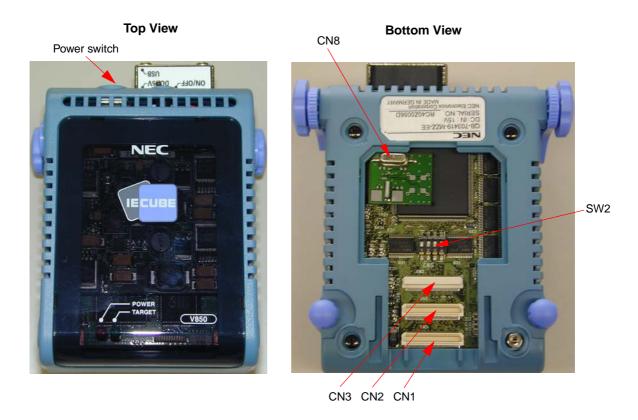
See 2.8 "Connecting USB Interface Cable and AC Adapter" on page 38.

### (7) Power application/shutdown

See 2.9 "Power Application/Shutdown" on page 38.

### 2.1 Names and Functions of Hardware

Figure 2-1: Names and Functions in QB-703425



### (1) CN1, CN2, CN3

These are connectors used to connect the exchange adapter or extension probe.

### (2) Clock adapter board connector (for clock) CN8

This is a clock adapter board used for mounting the crystal.

A 4.000 MHz crystal and capacitors, that configure an oscillator circuit are mounted at shipment.

(See 2.3 "Clock Settings" on page 26 for details.)

### (3) SW2

This is a switch whose setting should be set in case of special emulation. It is set to default at shipment.

(See 2.4 "Target IECUBE Settings" on page 28 for details.)

### (4) POWER (red LED)

This is an LED that indicates whether or not the power to IECUBE is on.

LED Status	IECUBE Status	
Lit	The power supply is on.	
Extinguished	The power supply is off, or the AC adapter is not connected to IECUBE.	
Blinking	An error has occurred internally. (Contact an NEC Electronics sales representative or distributor.)	

### (5) TARGET (green LED)

This is an LED that indicates whether or not the power to the target system is on.

LED Status	Target System Status	
Lit	The power supply to the target system is on.	
Extinguished	The power supply to the target system is off, or the target system is not connected.	

### (6) Power supply switch

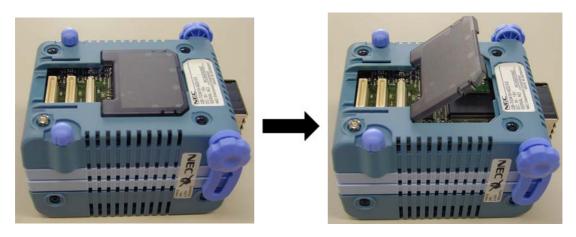
This is a power switch for IECUBE. This switch is turned off at shipment.

### 2.2 Removing Acrylic Board

Remove the acrylic board on the bottom surface of IECUBE before changing the settings of jumpers or clocks.

The acrylic board can be removed by pulling it up.

Figure 2-2: Removing Acrylic Board



### 2.3 Clock Settings

### 2.3.1 Overview of clock settings

**Note:** Default setting at shipment: clock adapter board is plugged in. There is no need to change the clock settings for standard use. Only in case of special setting required by customer this is described herewith.

Two methods are available for setting the clock.

See 2.3.2 "How to set clock" on page 26 for details.

- (1) Use the 4.000 MHz/32.768 kHz crystals mounted on the clock board on IECUBE as the internal clock.
- (2) Mount different 4.000 MHz/32.768 kHz types of crystals onto the clock board on IECUBE. This is only an option if same type of crystal as on the target system will be used.
- (3) The clock input from target system without using clock board one IECUBE Note

**Note:** The IECUBE does not support clock input from the target system. The function by using target system clock is not guaranteed.

### 2.3.2 How to set clock

A list of hardware settings for when the clock is set is shown in Table 2-1.

Table 2-1: List of Hardware Settings When Clock Is Set

Clock to Be Used	Parts Board
Use the 4.00 MHz / 32.768 kHz crystal mounted on the clock board as the internal clock.	Use the factory setting
Mount different crystals on the clock board and use it as the internal clock.  The frequency of the crystal that can be used is the same as that of the target device 4MHz.	Mount the crystal on the parts board.

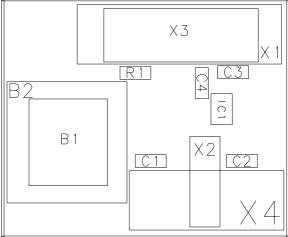
Settings other than above are prohibited.

### 2.3.3 How to change crystal

<1> Remove the clock adapter board. Be careful not to damage IECUBE. Resolder the parts of X1 and X2 by another type. Plug in clock adapter board again.

Figure 2-3: Clock Adapter Board - Parts Assembling





- <2> Default mounted
- <3> X1: crystal 4.000 MHz SMD type \*
  - X2: crystal 32.768 kHz DIL type \*
    - \* additional 10 pF capacitor on X1,X2 and XT1,XT2 each are assembled on default on the I/O-board.
- <4> Solder-mount the crystal and capacitor on the parts board supplied with IECUBE as follows.
- <5> X1 replace by X3: crystal DIL type
  - X1 replace by B1: oscillator DIL type, additional IC1 and R1 must be assembled X1 replace by B2: oscillator SMD type, additional IC1 and R1 must be assembled
  - X2 replace by X4: crystal SMD type

Reference(s)	Value
CN1	SAMTEC/TFM-110-02-S-D-AK
X1	4.000 MHz
X2	32.768 kHz
X3	4.000 MHz
X4	32.768 kHz
IC1	IDT74ALVC1G125DY
B2	4.000 MHz / 3.3 V
R1	R33
C1, C2, C3, C4	10 pF
B1	4.000 MHz / 3.3 V

### 2.4 Target IECUBE Settings

The SW2 setting varies depending on the target device / selected options. Settings other than below are prohibited.

Sw.	Setting	Function
1	On	Emulator option: Target power detection check for all $V_{DD}$ pins. $(AV_{DD},BV_{DD},DV_{DD},SMV_{DD},V_{DD})$
	Off*	Emulator option: Target power detection check for $V_{\mbox{\scriptsize DD}}$ pins only
2	On*	Emulator option: AV <sub>DD</sub> power switched by target
	Off	Emulator option: ${\rm AV}_{\rm DD}$ power fixed to internal 5.0V independent from target power detection.
3	On	Setting prohibited
	Off*	Fixed setting
4	On	Setting prohibited
	Off*	Fixed setting

Remark: Default settings are marked with a \*.

### 2.5 Software Setup

### 2.5.1 When ID850 debugger is used

See the document "ID850QB Operating Precautions" attached to the ID850 debugger for details.

### 2.5.2 When a debugger other than ID850QB (such as Multi) is used

See the user's manual of the debugger to be used and the IECUBE Setup Manual.

To connect to the emulator with GHS Multi debugger, use the following command line: (For complete information about option settings and configuration commands refer to the V850/850E ICE Server Reference Manual)

```
connect 850eserv -iecube -tc
  option -iecube: Connects through USB to IECUBE
  option -tc: Specifies that the target board be connected to IECUBE.
  If you specify this option, it detects unusual power status. Be sure to    power on. (refer to GHS V850/850E ICE Server)
```

### To set the clock, use the following command line:

```
target dclock 4000 32768
configuration command: Sets the target's minimum operating frequencies
DCLOCK [main_clock sub_clock]
main_clock: specifies main clock per kHz
sub_clock: specifies sub clock per Hz
```

#### 2.5.3 Download speed

The download speed can be increased (main clock) to a higher frequency. The base frequency must be set with the dclock command to the minimum main clock 4.000 MHz and the minimum subclock 32.768 kHz. Use the "hspload" command to allow fast download speed.

### Example .rc file

```
//
// Test.rc
//
//***********************
   connect 850eserv -df=DF3425J.800 -ip=.\DeviceFile\ -iecube -tc
   target dclock 4000 32768 swoff
// unmask/mask target pins
   target pinmask k;
   target pinmask WAIT;
// load program to memory
   hspload on;
   load;
// display opcodes in ASM view
   eval $_OPCODE = 1;
   eval $_ASMCACHE = 0;
// setup GUI
   button Reset {target reset;}
   button Trace {target trace a; tracewin;}
   button ViewMemory memview 0x00000000;
// target reset a; // reset CPU (and emulator/trace)
// open target window
   target window;
// indicate success
   echo"";
   echo "----";
   echo "Initialization done.";
   echo "";
//************* EOF **
```

### 2.6 Mounting and Connecting Connectors

### 2.6.1 Use

### (1) When mounting NQPACK144SD to target system

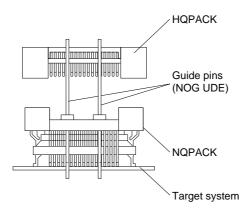
- <1> Coat the tip of four projections (points) at the bottom of the NQPACK144SD with two-component type epoxy adhesive (cure time longer than 30 min.) and bond the NQPACK144SD to the target system. If not bonded properly, the pad of the printed circuit board may peel off when the emulator is removed from the target system. If the lead of the NQPACK144SD does not coincide with the pad of the target system easily, perform step <2> to adjust the position.
- <2> To adjust the position, insert the guide pins for position-adjustment (NQGUIDE) provided with NQPACK144SD into the pin holes at the upper side of NQPACK144SD (refer to **Figure 2-4**). The diameter of a hole is  $\phi = 1.0$  mm. There are three non-through holes (refer to **APPENDIX A DIMENSIONS**).
- <3> After setting the HQPACK144SD, solder NQPACK144SD to the target system. By following this sequence, adherence of flux or solder sputtering to contact pins of the NQPACK144SD can be avoided.

• Recommended soldering condition...Reflow : 240°C, 20 sec. max.

Partial heating : 240°C, 10 sec. max. (per pin row)

<4> Remove the guide pins.

Figure 2-4: Mounting of NQPACK144SD



Remark: NQPACK144SD: Connector for target connection

HQPACK144SD: Cover for device installation

### (2) When setting device

Caution: Check for abnormal conditions such as resin burr or bent pins before setting a device to the NQPACK144SD. Moreover, check that the hold pins of the HQPACK144SD are not broken or bent before setting HQPACK144SD. If there are broken or bent pins, fix them with a thin, flat plate such as a blade.

- <1> Make sure that the NQPACK144SD is clean and the device pins are parallel (flat) before setting a device to the NQPACK144SD. Then, after mounting the NQPACK144SD to the target board, set the device and HQPACK144SD (refer to **Figure 2-5**).
- <2> Using the screws provided with the HQPACK144SD (four locations:  $M2 \times 6$  mm), secure the HQPACK144SD, device, and NQPACK144SD.

Tighten the screws in a crisscross pattern with the provided screwdriver or driver with torque gauge (avoid tightening strongly only one screw). Tighten the screws with 0.55 kg·f·cm (0.054 N·m) max. torque. Excessive tightening may diminish conductivity.

At this time, each pin is fixed inside the plastic wall dividers by the contact pin of the NQPACK144SD and the hold pin of the HQPACK144SD (refer to **Figure 2-6**). Thus, pins cannot cause a short with pins of neighboring devices.

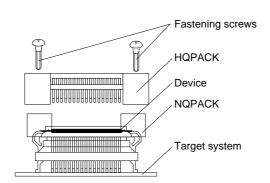
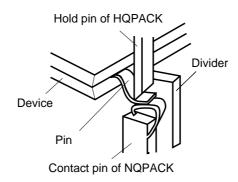


Figure 2-5: Mounting Device

Figure 2-6: NQPACK144SD and Device Pin



### **Chapter 2 IECUBE Setup Procedure**

### 2.6.2 Cautions on Handling Connectors

- (1) When taking connectors out of the case, remove the sponge while holding the main unit.
- (2) When soldering the NQPACK144SD to the target system, cover the HQPACK144SD to protect it against splashing flux.

Recommended soldering conditions Reflow : 240°C, 20 sec. max.

Partial heating: 240°C, 10 sec. max. (per pin row)

- (3) Check for abnormal conditions such as resin burr or bent pins before setting a device to the NQPACK144SD. Moreover, check that the hold pins of the HQPACK144SD are not broken or bent before setting HQPACK144SD. If there are broken or bent pins, fix them with a thin, flat plate such as a blade.
- (4) When securing the YQPACK144SD (connector for emulator connection) or HQPACK144SD to the NQPACK144SD with screws, tighten the four screws temporarily with the provided screwdriver or driver with torque gauge, then tighten the screws in a crisscross pattern (with 0.054 N·m max. torque).

Excessive tightening of only one screw may diminish conductivity.

If the conductivity is diminished after screw-tightening, stop tightening, remove the screws and check whether the NQPACK144SD is stained and make sure the device pins are parallel.

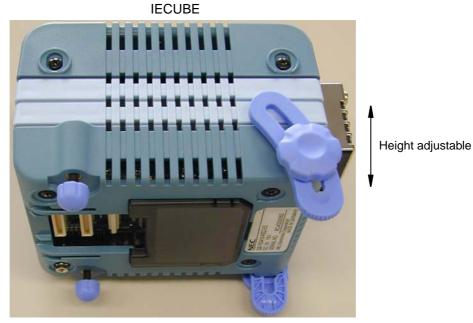
(5) Device pins do not have high strength. Repeatedly connecting to the NQPACK144SD may cause pins to bend. When setting a device to the NQPACK144SD, check and adjust bent pins.

### 2.7 Connecting IECUBE to Target System

### 2.7.1 Connection without using extension probe (QB-208-EP-01S)

IECUBE can be connected to the target system without using the extension probe. When connecting IECUBE and the target system, adjust the height of IECUBE using the rear spacer so that no stress is applied to the exchange adapter and target connector. In addition, take care to maintain insulation with the target system.

Figure 2-7: Connection without using Extension Probe



Exchange adapter

Mount adapter

Target connector

### 2.7.2 Connection using extension probe (QB-208-EP-01S)

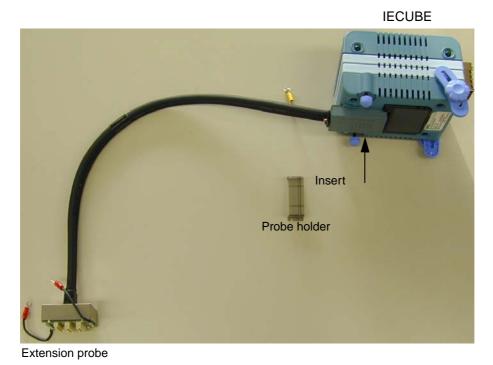
When using the extension probe (QB-208-EP-01S), connect IECUBE and the target system using the following procedure.

### (1) Connecting probe holder

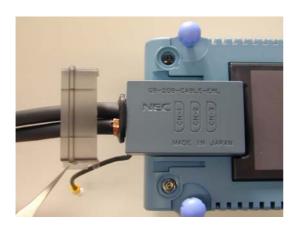
Use the probe holder (included with IECUBE) for connecting the extension probe to IECUBE. How to connect is shown below.

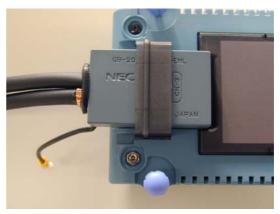
Figure 2-8: How to use Probe Holder

### <1> Connect IECUBE and the probe



### <2> Insert the probe holder in IECUBE





Insert the probe holder until it clicks (take care with the direction).

#### (2) Connecting extension probe GND lines

The extension probe has three GND lines. Connect these lines to IECUBE and the target system using the following procedure.

- <1> Fix a GND line of the extension probe to the nut on the bottom surface of IECUBE using a #0 or #1 precision cross-headed screwdriver.
- <2> Insert the connector on the top surface of the extension probe in the connector at the bottom opening of IECUBE from the lower side. Take care with the direction.

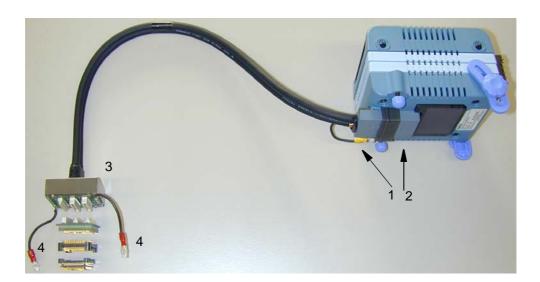


Figure 2-9: Connection of GND Lines

- <3> Connect the exchange adapter and extension probe to the target connector.
- <4> Connect two GND lines of the extension probe on the target system side to the GND block of the target system. If the pin or screw is fixed on the GND block of the target system, remove the transparent pin cover at the top of the GND line and fix the Y-branch pin of the GND line to the target system. In the same manner, if the GND pad on the target system is exposed, fix the Y-branch pin to the pad on the target system by soldering. (Recommended iron temperature: 300°C)
- <5> If there is only one GND connector on the target system, connect one side and cut off the other GND lines using nippers, or leave it as is without removing the pin cover.

<6> The length of the GND line shank (insulation block) is approximately 60 mm. Therefore, as shown in Figure 2-10, at least one connectable GND is necessary within a radius of approximately 60 mm from the three locations on the extension probe at which the target system is connected. The GND lines on the emulation probe are soldered at the position of J and K in Figure 2-10. When soldering the GND line at the position of L or M, remove a GND line soldered at J or K and solder it at L or M.

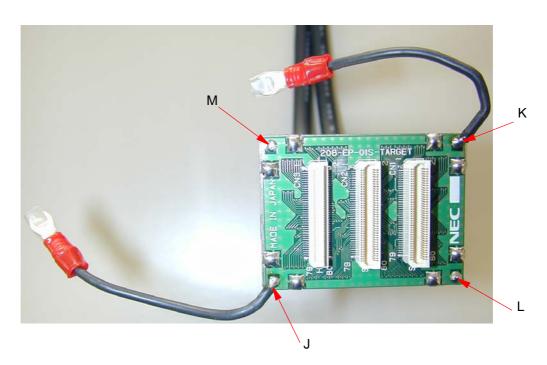


Figure 2-10: Location at which GND Line can be connected

#### (3) Maintaining insulation

When IECUBE and the target system are connected using the extension probe, adjust the height of IECUBE using the front spacer and rear spacer in order to maintain insulation with the target system.

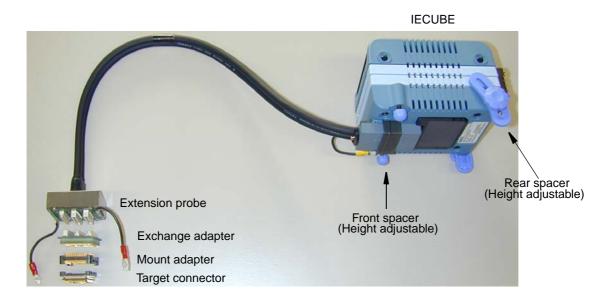


Figure 2-11: Connection when using Extension Probe

#### (4) Cautions on using extension probe

Note the following points when using the extension probe.

- Be careful so that stress from the extension probe is not applied to the target connector. Hold
  the exchange adapter with your fingers when removing it so that no stress is applied to the
  target connector.
- Be sure to connect the GND line of the extension probe to IECUBE and the target system; otherwise the impedance of the cable becomes unstable, which may cause degradation of the signal transmission characteristics or distortion of the output waveform with respect to the input waveform.
- If the external bus interface is used when the extension probe is used, increase the data wait by one. (Increase the value set to the DWC register by one.)

# 2.8 Connecting USB Interface Cable and AC Adapter

Connect the computer and IECUBE using the USB interface cable supplied with IECUBE. Insert the power supply connector on the rear side of IECUBE and insert the AC adapter plug supplied with IECUBE in the outlet. See Figure 2-12 for the connector position of IECUBE.

The AC adapter can support voltages from 100 V to 240 V by exchanging the AC plug. A 100 V AC plug is mounted at shipment. To use IECUBE with 220 V or 240 V, exchange the AC plug for one that supports 220 V or 240 V (both included with IECUBE).

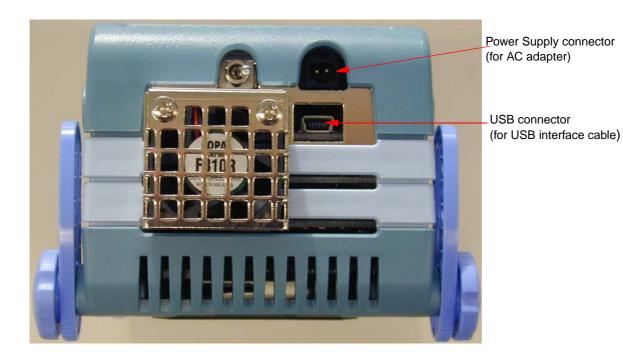


Figure 2-12: Connector Position

# 2.9 Power Application/Shutdown

Be sure follow the sequence shown below when activating or terminating the emulator; **otherwise the target system or IECUBE may be damaged**.

- When activating the emulator:
   Apply power to IECUBE → Apply power to the target system<sup>Note</sup> → Activates the debugger.
- When terminating the emulator:
   Terminate the debugger → Shut down power to the target system → Shut down power to IECUBE.

**Note:** This step is not required when the target system is not connected.

# **Chapter 3** List of Factory Settings

Table 3-1: List of Factory Settings

Item	Settings	Remark
SW2		See 2.4 "Target IECUBE Settings" on page 28 for details. For QB-703425-MZZ-EE fac- tory setting changed. See 2.4
CN8	NEC. JAPAN 1911 31 19 19 19 19 19 19 19 19 19 19 19 19 19	The clock adapter board is plugged on CN8. See 2.3 "Clock Settings" on page 26 for details.
Power supply switch	ON/OFF DC:15V-	This switch is turned off at shipment.

[MEMO]

### Chapter 4 Differences Between Target Device and IECUBE

This chapter explains the differences on using the IECUBE to the V850E/Dx3 devices.

There are three User's manuals important, covering the specific description of the V850E/Dx3 devices, the Core Architecture (V850E1) and the IECUBE.

Refer to these versions or later version:

#### Device:

<1>	Hardware UM	-V850E/Dx3	U17566EE1V0UM00	or - current version
<2>	Architecture UM	-V850E/Dx3	U14559EJ3V1UM00	or - current version
<3>	Operating Precautions CN	-V850E/Dx3	Dx3 OP's	or - current version

#### QB-703425:

<4>	Operating Precautions CN	-QB-703425	EEDT-OP-0027-5.0	or - current version
<5>	IECUBE UM (this manual)	-QB-703425	U17678EE1V0UM00	or - current version

Note: Download the documents from the NEC Electronics (Europe) GmbH web site.

URL: http://www.eu.necel.com/products/micro/

#### 4.1 Functions Emulated Differently

The following listed functions are emulated different to the device  $\mu PD703420$ ,  $\mu PD70(F)3421$ ,  $\mu PD7053423$ ,  $\mu PD70F3423$ ,  $\mu PD70F3424$ ,  $\mu PD70F3425$ .

<1> POC - emulated by a discrete circuit

<2> Interface Pins - emulated by a different logic circuit as on the device

<3> RESET - emulated by discrete circuit
<4> MODE switch - not used and not emulated

<5> IRAM behaviour - the contents after power on might differ

#### 4.1.1 Differences by emulating POC

Via a comparator device, the target  $V_{DD}$  power is checked against the POC threshold voltage, set to 3.35 V value typical (3.2 V min. and 4.0 V max.). This detection information will be used for emulating the POC function.

#### 4.1.2 Differences on Interface Pins (Electrical Characteristics)

The electrical characteristic of these pins which are different emulated as these pins on the device μPD703420, μPD70(F)3421, μPD703422, μPD70F3423, μPD70F3424, μPD70F3425.

<1> Ports numeric - no difference

<2> Clock - XT1, XT2, X1, X2 not used Note 1

<3> Power - internal supply in standalone mode (no target connected) Note 2

- External supply on  $\mathrm{AV}_\mathrm{DD},\,\mathrm{BV}_\mathrm{DD},\,\mathrm{DV}_\mathrm{DD},\,\mathrm{SMV}_\mathrm{DD},\,\mathrm{V}_\mathrm{DD}$ 

In both modes, the power consumption might differ to the device.

<4> Ground - there is a common ground used

- One ground pin ( $V_{SS50}$ /pin63) will be used for target connection detection.

A pull up of 10 k $\Omega$  is used

<5> RESET - A pull down of 47 kΩ is used. The input characteristic differs.

<6> FLMD0 - Not used. The input characteristic differs.

<7> REGCx - A 4.7 μF and a 100 nF capacitor is used in parallel. The input characteristic

differs.

The electrical characteristic of all signals will be different to the device  $\mu PD703420$ ,  $\mu PD70(F)3421$ ,  $\mu PD703422$ ,  $\mu PD70F3423$ ,  $\mu PD70F3424$ ,  $\mu PD70F3425$ . This is based on the PCB wiring, all used connectors and the target probe wiring. These results in an additional load on all pins and therefore the characteristic and the timing of the signals will be influenced. This should be taken into consideration by using the IECUBE on the target board.

The current in the standby modes can not be emulated.

**Notes: 1.** The usage of the crystals on target is not supported.

Table 4-1: Clock Connector CN8

Target X1	1	2	IECUBE X1
Target X2	3	4	IECUBE X2
	5	6	
	7	8	
Target XT1	9	10	IECUBE XT1
Target XT2	1	12	IECUBE XT2

#### 2. The power structure of the IECUBE is as following

Using the IECUBE in standalone mode, the power will be supplied internally fixed to 5.0 V for all power pins and AV<sub>REF</sub> In standalone mode, no target system connection is allowed. Using the IECUBE in target mode, the availability of the target will be checked by V<sub>SS50</sub>/pin63. This pin is connected internally to a 10 k $\Omega$  pull-up. The connected target board provides a ground connection at this pin. This is the indication, that the target system is available. All power pins are connected to the power pins of the emulation device via an analogue switch directly.

V <sub>SS50</sub> / pin63	Power used from	Mode	Power checked on	AV <sub>DD</sub> /AV <sub>REF</sub>	AV <sub>DD</sub> /AV <sub>REF</sub>
Target connection	Target/ internal	SW2 switch1	> 2.7 V	SW2 switch2	Power used from
open	internal	-	-	-	-
GND	target	on	all power pins	on	target
				off	internal
		off	on V <sub>DD</sub> pins only <sup>Note</sup>	on	target
				off	internal

Note: All other power pin must supply a voltage in the defined range.

#### 4.1.3 Differences by emulating RESET

The  $\overline{\text{RESET}}$  function is emulated by using different input buffer. The input characteristic differ. An additional 47 k $\Omega$  pull down resistor is connected. This must be observed on target interface. Therefore the timing might be different.

#### 4.1.4 Differences by emulating MODE switch

This input level will not be checked by the IECUBE.

#### 4.1.5 iRAM

The content of the iRAM will be unchanged after a RESET/Target Power off/on. This behavior may differ from the real device. In the real device the contents of the iRAM may change to that contents before a RESET/Power off/on.

#### 4.1.6 FOUT- and WDT-clock supply differ from device in standby mode

#### (1) Details:

In standby mode, the FOUT clock supply (Ring-clock, if ROSTP=1 is set) will not stop. In standby mode, the FOUT clock supply (Sub-clock, if SOSTP=1 is set) will not stop.

In standby mode, the WDT clock supply (Ring-clock, if ROSTP=1 is set) will not stop. In standby mode, the WDT clock supply (Sub-clock, if SOSTP=1 is set) will not stop.

#### (2) Workaround:

None

#### 4.1.7 PSM.OSCDIS reset value different to device

#### (1) Details:

The reset value of the OSCDIS is '1'. On real chip OSCDIS is set to '0' during firmware execution.

#### (2) Workaround:

Initialise the OSCDIS after RESET or use the functions of the Debugger to initialize the OSCDIS before program start.

#### 4.1.8 Timing different to device for oscillation stabilization time

#### (1) Details:

The oscillation stabilization time indicated by OSCSTAT differs to real device. In emulation mode the oscillator runs permanently, so the time for oscillation start is not the same.

After reset, out of the different OSCDIS setting, the oscillation stabilization counter start is different.

#### (2) Workaround:

None

#### 4.1.9 Break precaution related to ADC macro

#### (1) Details:

The following behaviour is valid for the IECUBE emulator "only" in case the peripheral break mode is active for the ADC macro:

<1> In case the peripheral break signal (SVSTOP = 1) is set while or after the conversion control bit ADA0CE has been set, the AD conversion is not started and the concerned interrupt INTAD will not be generated. Furthermore the AD conversion will not start conversion even in case the Supervisor mode has been left and the debugger operates in RUN mode.

In case the ADA0CE bit will be set during normal RUN mode again without issuing the peripheral break signal, the ADC will operate as specified.

The conditions the peripheral break signal is issued are as follows:

a.) When one of these break is executed on the AD0ACE bit write instruction Software break

Before-execution hardware break

After-execution hardware break

b.) When one of these break is executed on the first instruction following the AD0ACE bit write instruction

Software break

Before-execution hardware break

c.) When the following break is executed on the second instruction following the AD0ACE bit write instruction

Software break

<2> In case the peripheral break mode (SVSTOP=1) has been configured and the debugger operates in the debug (supervisor-) mode, a write operation to the ADC concerned registers: ADA0M0, (ADA0M1(#)), ADA0M2, ADA0S, ADA0PFT, ADAPFM (#) when ADA0CE=1, the re-write of ADA0M1 is prohibited and will not cause the start of the ADC's reconversion. It doesn't make a difference if the concerned write operations to the above mentioned ADC registers are executed via the debugger itself or via DMA that is not stopped when entering the supervisor mode. Both write operations will cause the limitation.

#### Chapter 4 Differences Between Target Device and IECUBE

#### (2) Workaround:

<1> When a software break is executed in case the peripheral break mode has been configured for the ADC macro, set the software break not for the instruction the ADA0CE bit is set or at one of the following two instructions:

#### Example:

```
set1 7, ADA0M0 --- software break is prohibited
nop --- software break is prohibited
nop --- software break is prohibited
nop --- software break is prohibited
--- software break is possible to set from here on
```

<2> When a "before-execution hardware break" is executed and the peripheral break mode has been configured for the ADC macro, don't set that breakpoint for the instruction that sets the ADA0CE bit or for the following instruction:

#### Example:

```
set1 7, ADA0M0 --- before-execution hardware break is prohibited --- before-execution hardware break is prohibited nop --- before-execution hardware break is possible to set from here on
```

<3> When a "before-execution hardware break" is executed in peripheral break mode and the peripheral break mode has been configured for the ADC macro, don't set that breakpoint for the instruction that sets the ADA0CE bit:

#### Example:

```
set1 7, ADA0M0 --- after-execution hardware break is prohibited --- after-execution hardware break is possible to set from here on
```

- <4> When users want to proceed the write operation for the AD related registers during BREAK (debugger operates within the supervisor mode), don't use peripheral break mode.
- <5> When users want to proceed the DMA transfer which has AD related registers set as source/ destination for this DMA transfer <<<, don't use peripheral break mode.</p>

**Note:** In case a condition mentioned under "Workarounds: <1>, <2>, <3>)" will occur when setting one of the concerned breakpoints on the location of an interrupt-vector, no limitation will become valid due to the clock-cycles that are requested for the interrupt-response time!

#### 4.2 Notes on Emulation

The following listed notes shall be observed by using IECUBE.

<1> register - access in break mode

<2> register - access if software break is set

<3> trace - display order

<4> instruction ex. - execution of instructions if hardware break is set

<5> memory area - non map break

<6> instruction ex. - guarded area access break delay <7> internal RAM - do not use simultaneous DMA transfer

#### 4.2.1 Access to CPU register DBPSW, DBPC, ECR

DBPSW, DBPC and ECR cannot be accessed in break mode. If written, the value is discarded, if read 0 is always read.

#### 4.2.2 PSC register access

#### (1) Details:

The debugger hangs up if a software break is set at the NOP instruction immediately after the PSC register is accessed.

#### (2) Workaround:

#### **Example:**

MOV 0x2, R1 ST.B R1, PRCMD ST.B R1, PSC

NOP <- The debugger hangs up if a software break is set here

NOP <- Setting a software break hereafter causes no problem

Use a hardware break to set a break immediately after the PSC register is accessed.

#### 4.2.3 Trace display order of data access trace

#### (1) Details:

When the trace mode - Data access trace - is enabled to display the access history the displayed order may be reversed in the following cases:

- (a) When a write instruction follows a read instruction.
- (b) When a bit manipulation instruction that performs a read/modify/write operation (SET1, NOT1, CLR1) is performed

The trace result is displayed in the following order: 1st: write, 2nd: read.

The reversed trace display order is related to the read data accesses only, because instructions and data accesses will be output by the DCU separately and each information belongs to different trace packages. With a "Store" instruction the corresponding data are available immediately, with a "Load" instruction the data access has to be executed first to get the corresponding data.

#### (2) Workaround:

Use TraceMode: BranchPC + DataAddress + Data + DataAccessPC. In this case the trace data could be classified correctly, because also DataAccessPC is available.

#### 4.2.4 Simultaneous execution of two instructions when hardware break is set

#### (1) Details:

Suppose that two instructions "instruction A" followed by an "instruction B" are executed simultaneously. The execution result of these instructions when a hardware break is set is shown in the table below. As a result the break may occur at a different location from the set address, or the break may even not occur.

The meaning of simultaneously is as follows: Two consecutive instructions are processed at the same time inside the pipeline (at different stages). A real simultaneous execution is not possible in the V850E core.

Break Timing					
No.	Instruction A	Instruction B	Execution Result		
1	Break before execution	No break setting	Break before execution of A		
2	Break after execution	No break setting	Break after execution of B		
3	No break setting	Break before execution	Break before execution of A		
4	No break setting	Break after execution	Break after execution of B		
5	Break before execution	Break before execution	Break before execution of A		
6	Break before execution	Break after execution	Break before execution of A and after execution of B		
7	Break after execution	Break before execution	Break before execution of A and after execution of B		
8	Break after execution	Break after execution	Break after execution of B		

#### (2) Workaround:

To avoid the above behaviour set a software break instead of a hardware break.

#### 4.2.5 Non map break

#### (1) Details:

If a program fetch is performed on an unused memory area in the emulator normally a non map break occurs. However the non map break is not generated in the top 16 bytes of unused areas.

#### (2) Workaround:

None

#### 4.2.6 Guarded area access break delay

#### (1) Details:

When a guarded area is entered by a jump instruction or a illegal sfr access is detected, the guard access break is delayed for approximately 5 instruction cycles. The exact cycles required for this detection is not determinable due to the internal detection structure of the IECUBE.

#### (2) Workaround:

None

#### Chapter 4 Differences Between Target Device and IECUBE

# 4.2.7 Break during program execution in internal RAM

#### (1) Details:

An unexpected break may occur when a peripheral I/O register is accessed during program execution from internal RAM.

#### (2) Workaround:

Cancel the fail-save break setting for the internal RAM in the debugger.

When using Green Hills Multi:

Cancel the fail-save break for "ramgrd" and "ramgrdv" using the Target command "flsf".

# 4.2.8 Program execution in internal RAM and simultaneous DMA transfer access to/from internal RAM

Note: This behaviour does only occur on device, not on IECUBE.

#### (1) Details:

When executing one of the following instructions, located in the internal RAM, do not execute a DMA transfer that transfers data to/from the internal RAM (transfer source/destination), because the CPU may not operate correctly afterwards:

A bit manipulation instruction (SET1, CLR1 or NOT1)

#### (2) Unaffected cases

The critical situation does not occur if no instruction is executed in the internal RAM, or no DMA transfer is performed on the internal RAM.

## (3) Workaround:

Implement any of the following workarounds:

Workaround

- Do not perform DMA transfers to the internal RAM when these instructions are executed from internal RAM.

# 4.3 Functions Not Supported

- <1> ROM correction Note
- <2> Flash self programming
- <3> N-Wire

**Note:** The ROM correction function is not supported. The IECUBE supplies "dummy" register's as space holder for the ROM correction SFR's only. The access time of these registers are not identical to these of the real device.

[MEMO]

# **Chapter 5 Notes on Target System Design**

This chapter explains notes on target system design, including areas in which parts should not be mounted on the target system and the area that has a height restriction on the mounting parts. This areas differ by using space adapter or target probe.

The 144-pins QFP target probe connectors are required for the  $\mu$ PD703420,  $\mu$ PD70(F)3421,  $\mu$ PD70F3422,  $\mu$ PD70F3423,  $\mu$ PD70F3425.

The following package type is used:  $\mu PD70F342x$ -GJ-UEN: 144 QFP 20 mm  $\times$  20 mm / 0.5 mm

All drawings views are from top.

#### 5.1 When Extension Probe Is Not Used

#### 5.1.1 V850E/Dx3 - 144-pin

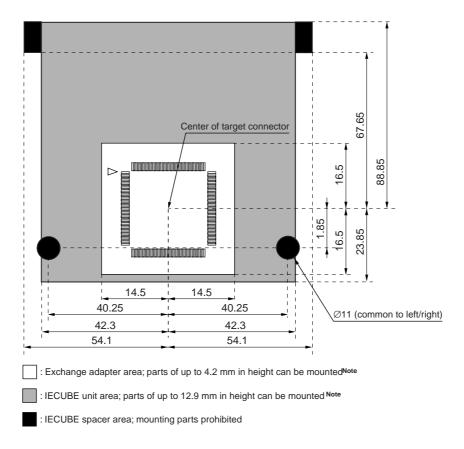


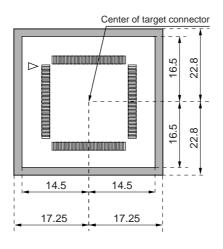
Figure 5-1: V850E/Dx3 - 144-pin

**Note:** The height can be adjusted using the spacer adapter (can increase by 5.6 mm per unit)

#### 5.2 When Extension Probe Is Used

#### 5.2.1 V850E/Dx3 - 144-pin with probe

Figure 5-2: V850E/Dx3 -144-pin with probe



- : Exchange adapter area; parts of up to 4.2 mm in height can be mounted Note
- : Extencion probe top area; parts of up to 25.0 mm in height can be mounted Note

Note: The height can be adjusted using the spacer adapter (can increase by 5.6 mm per unit)

# **Chapter 6 Connector Probe Package Drawings**

# **6.1 Target Connector**

☐ 27 0.5x35=17.5  $\square$  23 0.37 12 0.37 C1.53-R1.5 TET 22.65 144 SD 0.37 4-12.0 (A projection height: 1.8mm) 0.379.45

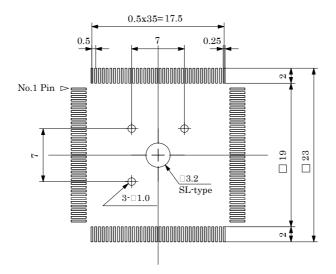
0.5

21.05

Figure 6-1: Target Connector for 144-pin

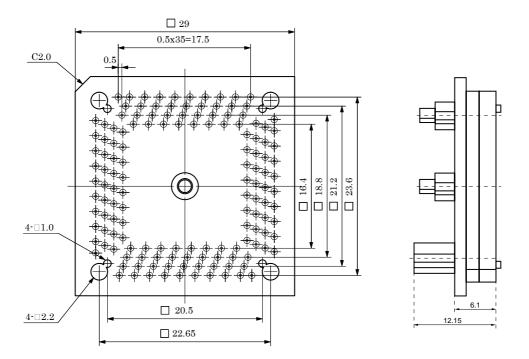
# **6.2 Foot Patterns of Target Connectors**

Figure 6-2: Foot Pattern of Target Connector for 144-pin



# 6.3 Exchange Adapter

Figure 6-3: Exchange Adapter for 144-pin



# 6.4 Mounting Adapter

29 0.5X36=17.5 7 TET 4-12.2

Figure 6-4: Mounting Adapter for 144-pin

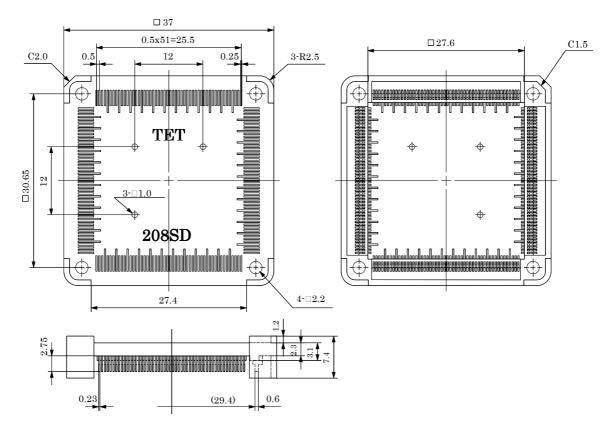


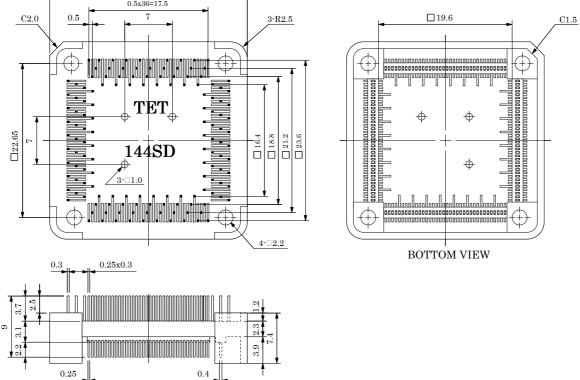
Figure 6-5: Mounting Adapter for 208-pin

<sup>\*</sup> Applicable size of IC package : IC body size  $28.0~\mathrm{x}~28.0~\mathrm{mm}$  IC outer size  $30.0~\mathrm{x}~30.0~\mathrm{mm}$ 

Figure 6-6: YQ Adapter for 144-pin

# 6.5 YQ Adapter

 $\square$  29 0.5x36=17.5  $\square$  19.6 C2.03-R2.5

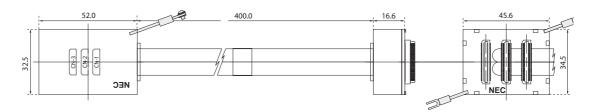


# 6.6 Spacer Adapter

Figure 6-7: Spacer Adapter for 144-pin

#### 6.7 Extension Probe

Figure 6-8: Extension Probe





Although NEC has taken all possible steps to ensure that the documentation supplied

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